

PCN97009A Data2

Reliability Testing Summary

Technology:	Si Gate CMOS
Device Type:	XC4025E & XC4013E
Package Type:	HQ240 Thermally Enhanced PQFP
Molding Compound:	Sumitomo 7304LC/F

	Pre. Cond. 0.0621% 30/60% 192 Hrs. 3 V.P. 219°C	85°C / 85% 1,000 Hrs.	Pressure Pot 96 Hrs. 121°C/2 Atm.	Temp. Cycle 542 Cys. -65°C / +150°C
Combined Started Lot:	1	1	1	1
Combined Completed Lots:	1	1	1	1
Failures:	0	0	0	0
Device on Test:	111	44	45	21
Actual Device Hours / Cycles:	21,312	44,000	4,320	11,382
Mean:	192	1,000	96	542
Physical Dimension:	Passed			
Solderability:	Passed			
Internal Visual:	Passed			
Lead Integrity:	Passed			
Peel Test / X-Ray:	Passed			